



EMI TEST REPORT

Test Report No. : 10249276H-B

Applicant : Sharp Corporation, Communication Systems Division.
Type of Equipment : Cellular Phone
Model No. : SH-04F
FCC ID : APYHRO00207
Test standard : FCC Part 15 Subpart B 2013 Class B
Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

Date of test: March 10, 2014

**Representative
test engineer:**

Keisuke Kawamura
Engineer of WiSE Japan,
UL Verification Service

Approved by :

Takahiro Hatakeda
Leader of WiSE Japan,
UL Verification Service



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.
*As for the range of Accreditation in NVLAP, you may refer to the WEB address,
<http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

UL Japan, Inc.

Head Office EMC Lab.

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13-EM-F0429

REVISION HISTORY

Original Test Report No.: 10249276H-B

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CONTENTS	PAGE
SECTION 1: Customer information	4
SECTION 2: Equipment under test (E.U.T.)	4
SECTION 3: Test specification, procedures & results	5
SECTION 4: Operation of E.U.T. during testing	8
SECTION 5: Conducted Emission	10
SECTION 6: Radiated Emission	11
APPENDIX 1: Data of EMI test	12
Conducted Emission	12
Radiated Emission	14
APPENDIX 2: Test instruments	18
APPENDIX 3: Photographs of test setup.....	19
Conducted Emission	19
Radiated Emission	20
Worst Case Position (Horizontal: X-axis/ Vertical:X-axis)	22

SECTION 1: Customer information

Company Name : Sharp Corporation, Communication Systems Division.
Address : 2-13-1 Iida Hachihonmatsu HigashiHiroshima-City, Hiroshima, 739-0192
Japan.
Telephone Number : +81-82-420-1838
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Contact Person : Hachiro Hidaka

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Cellular Phone
Model No. : SH-04F
Serial No. : Refer to Section 4, Clause 4.2
Receipt Date of Sample : March 7, 2014
Country of Mass-production : China
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product description

Feature of EUT : SH-04F is Quad-band LTE(B1/B3/B19/B21) and
Quad-band W-CDMA (FDD 1/5/6/19) and
Quad-band GSM(850/900/1800/1900) Cellular Phone.
The EUT has the function that Bluetooth, ANT+ wireless technology interface
and wireless LAN technical interface for establishing contact and transmitting
data with certain device.
Clock frequencies in the system : CPU: 2,260MHz (max)
RTC: 32.768kHz, 27.0MHz (I2C), 27.12MHz (NFC), 48.0MHz (WLAN/BT)
Source oscillation: 19.2MHz (CPU)

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SECTION 3: Test specification, procedures & results

3.1 Test specification

Test Specification : FCC Part 15 Subpart B: 2013, final revised on September 30, 2013 and effective October 30, 2013

Title : FCC 47CFR Part15 Radio Frequency Device
Subpart B Unintentional Radiators

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	ANSI C63.4: 2009 7. AC powerline conducted emission measurements	Class B	N/A	[QP] 4.8dB 0.17016MHz, L [AV] 5.9dB 0.17016MHz, L	Complied
Radiated emission	ANSI C63.4: 2009 8. Radiated emission measurements	Class B	N/A	9.6dB 639.008MHz, Vertical, QP	Complied

*Note: UL Japan, Inc's EMI Work Procedure 13-EM-W0420.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (+dB)
	150kHz-30MHz
No.1	3.5dB
No.2	3.5dB
No.3	3.6dB
No.4	3.5dB

Test room (semi-anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	4.0dB	5.1dB	5.0dB	5.1dB	6.0dB	4.9dB	4.3dB
No.2	3.9dB	5.2dB	5.0dB	4.9dB	5.9dB	4.7dB	4.2dB
No.3	4.3dB	5.1dB	5.2dB	5.2dB	6.0dB	4.8dB	4.2dB
No.4	4.6dB	5.2dB	5.0dB	5.2dB	6.0dB	5.7dB	4.2dB

*3m/1m/0.5m = Measurement distance

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. *NVLAP Lab. code: 200572-0
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN
Telephone : +81 596 24 8999 Facsimile : +81 596 24 8124

	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.0 x 4.5 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.8 x 4.6 x 2.8m	2.4 x 2.4m	-
No.11 measurement room	-	-	6.2 x 4.7 x 3.0m	4.8 x 4.6m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

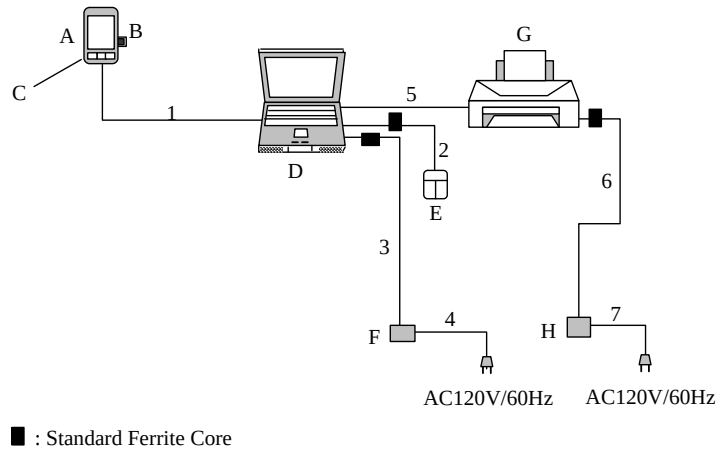
Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating modes

The mode(s) : 1) USB Data Com Mode
The USB data is communicated between EUT and Personal computer (Pair of EUT).
2) Standby Mode
Standby state for USB communication.

4.2 Configuration and peripherals



*Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Cellular Phone	SH-04F	004401/11/506548/0	Sharp Corporation	EUT
B	microSD Memory Card	SD-C02G	None	Toshiba	-
C	Lithium-Ion Battery	UBATIA242AFN1	P131224	Sharp Corporation	EUT
D	Personal Computer	PP11L	CN-0D4571-48643-58P-1053	Dell	-
E	Mouse	M-UAG120	LZ733B70EVV	Toshiba	-
F	AC Adapter (PC)	LA65NS1-00	CN-0YD637-71615-64Q-2243	Dell	-
G	Printer	895Cxi	SG8BA1W18J	Hewlett Packard	-
H	AC Adapter (Printer)	C4557-60004	C8L01B	Hewlett Packard	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	USB Data Cable	1.20	Shielded	Shielded	-
2	Mouse Cable	0.72	Unshielded	Unshielded	-
3	AC Adaptor Cable (PC)	1.76	Unshielded	Unshielded	-
4	AC Power Cable (PC)	1.70	Unshielded	Unshielded	-
5	Parallel Cable	1.65	Shielded	Shielded	-
6	AC Adapter Cable (printer)	2.00	Unshielded	Unshielded	-
7	AC Power Cable (printer)	1.75	Unshielded	Unshielded	-

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SECTION 5: Conducted Emission

5.1 Operating environment

Test place	: No. 1 semi anechoic chamber
Temperature	: See data
Humidity	: See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane.

The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from the LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment.

Photographs of the set up are shown in Appendix 3.

Frequency range	: 0.15 MHz-30MHz
EUT position	: Table top
EUT operation mode	: See Clause 4.1

5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type	: Quasi-Peak and Average
IF Bandwidth	: 9 kHz

5.4 Test result

Summary of the test results: Pass

Date: March 10, 2014

Test engineer: Keisuke Kawamura

UL Japan, Inc.

Head Office EMC Lab.

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SECTION 6: Radiated Emission

6.1 Operating environment

Test place : No. 1 semi anechoic chamber
Temperature : See data
Humidity : See data

6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane.

The EUT was set on the edge of the tabletop.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.

Photographs of the set up are shown in Appendix 3.

6.3 Test conditions

Frequency range : 30MHz-300MHz (Biconical antenna) / 300MHz-1000MHz (Logperiodic antenna)
1000MHz-12000MHz (Horn antenna)
Test distance : 3m
EUT position : Table top
EUT operation mode : See Clause 4.1

6.4 Test procedure

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The radiated emission measurements were made with the following detector function of the test receiver and the Spectrum analyzer.

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver	Spectrum Analyzer
IF Bandwidth	QP: BW 120kHz	PK: RBW:1MHz/VBW: 3MHz AV *1): RBW:1MHz/VBW:10Hz

*1) When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

- The noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at representative X-axis since no difference was found among each position.

6.5 Test result

Summary of the test results: Pass

Date: March 10, 2014

Test engineer: Keisuke Kawamura

UL Japan, Inc.

Head Office EMC Lab.

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APPENDIX 1: Data of EMI test

Conducted Emission

DATA OF CONDUCTED EMISSION TEST

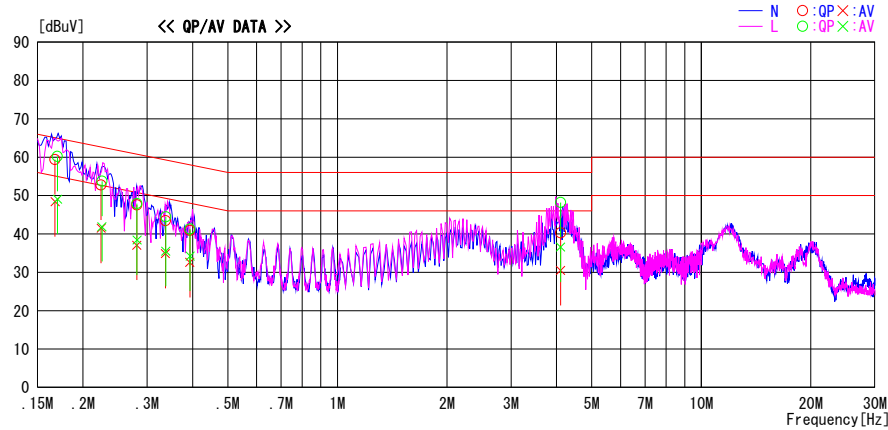
UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2014/03/10

Report No. : 10249276H

Temp./Humi. : 20deg. C / 32% RH
Engineer : Keisuke Kawamura

Mode / Remarks : USB Data Com Mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.16754	46.2	35.2	13.2	59.4	48.4	65.1	55.1	5.7	6.7	N	
0.22414	39.4	28.2	13.3	52.7	41.5	62.7	52.7	10.0	11.2	N	
0.28106	34.3	23.8	13.3	47.6	37.1	60.8	50.8	13.2	13.7	N	
0.33678	30.2	21.6	13.3	43.5	34.9	59.3	49.3	15.8	14.4	N	
0.39321	27.6	19.3	13.3	40.9	32.6	58.0	48.0	17.1	15.4	N	
4.10522	26.3	16.5	14.0	40.3	30.5	56.0	46.0	15.7	15.5	N	
0.17016	47.0	35.9	13.2	60.2	49.1	65.0	55.0	4.8	5.9	L	
0.22541	40.4	28.6	13.3	53.7	41.9	62.6	52.6	8.9	10.7	L	
0.28138	34.6	25.1	13.3	47.9	38.4	60.8	50.8	12.9	12.4	L	
0.33762	31.2	22.2	13.3	44.5	35.5	59.3	49.3	14.8	13.8	L	
0.39372	28.0	20.9	13.3	41.3	34.2	58.0	48.0	16.7	13.8	L	
4.10522	34.2	22.6	14.0	48.2	36.6	56.0	46.0	7.8	9.4	L	

CHART:WITH FACTOR,Peak hold data. CALCULATION:RESULT=READING+C.F(LISN LOSS+ATT LOSS +CABLE LOSS)
Except for the above table : adequate margin data below the limits.

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Conducted Emission

DATA OF CONDUCTED EMISSION TEST

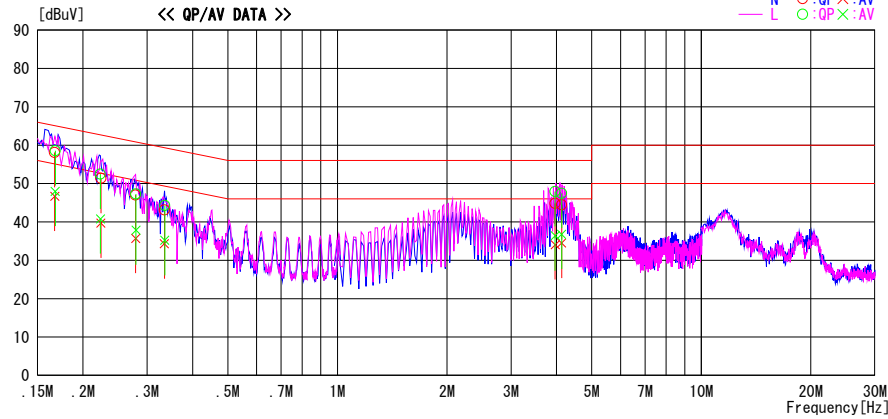
UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2014/03/10

Report No. : 10249276H

Temp./Humi. : 20deg. C / 32% RH
Engineer : Keisuke Kawamura

Mode / Remarks : Standby Mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.16712	44.9	33.5	13.2	58.1	46.7	65.1	55.1	7.0	8.4	N	
0.22384	38.1	26.4	13.3	51.4	39.7	62.7	52.7	11.3	13.0	N	
0.27889	33.7	22.4	13.3	47.0	35.7	60.8	50.8	13.8	15.1	N	
0.33481	29.8	21.0	13.3	43.1	34.3	59.3	49.3	16.2	15.0	N	
3.96455	30.8	20.1	14.0	44.8	34.1	56.0	46.0	11.2	11.9	N	
4.13316	30.5	20.5	14.0	44.5	34.5	56.0	46.0	11.5	11.5	N	
0.16770	45.4	34.8	13.2	58.6	48.0	65.1	55.1	6.5	7.1	L	
0.22332	39.2	27.5	13.3	52.5	40.8	62.7	52.7	10.2	11.9	L	
0.27961	34.0	24.6	13.3	47.3	37.9	60.8	50.8	13.5	12.9	L	
0.33534	31.0	21.9	13.3	44.3	35.2	59.3	49.3	15.0	14.1	L	
3.96709	33.9	22.4	14.0	47.9	36.4	56.0	46.0	8.1	9.6	L	
4.13316	33.5	22.8	14.0	47.5	36.8	56.0	46.0	8.5	9.2	L	

CHART:WITH FACTOR,Peak hold data. CALCULATION:RESULT=READING+C.F(LISN LOSS+ATT LOSS +CABLE LOSS)
Except for the above table : adequate margin data below the limits.

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Below 1GHz)

DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2014/03/10

Report No. : 10249276H

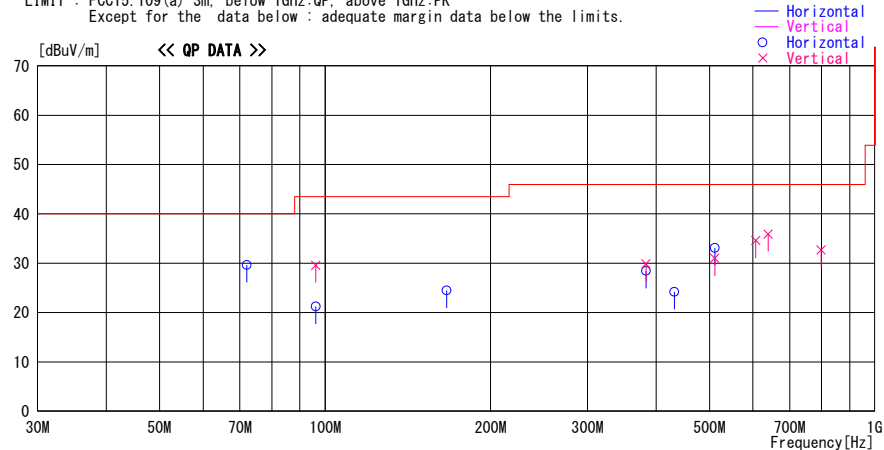
Temp./Humi. : 20deg. C / 32% RH

Engineer : Keisuke Kawamura

Mode / Remarks : USB Data Com Mode Worst-Axis (Hori: X / Vert: X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK

Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
72.022	54.0	QP	6.4	-30.8	29.6	104	275	Hori.	40.0	10.4	
96.134	41.9	QP	9.7	-30.4	21.2	229	205	Hori.	43.5	22.3	
96.134	50.3	QP	9.7	-30.4	29.6	146	100	Vert.	43.5	13.9	
166.267	38.6	QP	15.7	-29.8	24.5	103	205	Hori.	43.5	19.0	
383.453	40.4	QP	16.7	-27.2	29.9	208	143	Vert.	46.0	16.1	
383.453	38.9	QP	16.7	-27.2	28.4	254	100	Hori.	46.0	17.6	
431.863	33.5	QP	17.5	-26.8	24.2	139	100	Hori.	46.0	21.8	
511.267	41.1	QP	18.3	-26.3	33.1	120	100	Hori.	46.0	12.9	
511.267	39.0	QP	18.3	-26.3	31.0	38	151	Vert.	46.0	15.0	
607.130	40.7	QP	19.5	-25.6	34.6	300	100	Vert.	46.0	11.4	
639.089	41.6	QP	19.7	-25.4	35.9	170	100	Vert.	46.0	10.1	
798.172	35.4	QP	22.0	-24.7	32.7	82	100	Vert.	46.0	13.3	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION:RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Below 1GHz)

DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2014/03/10

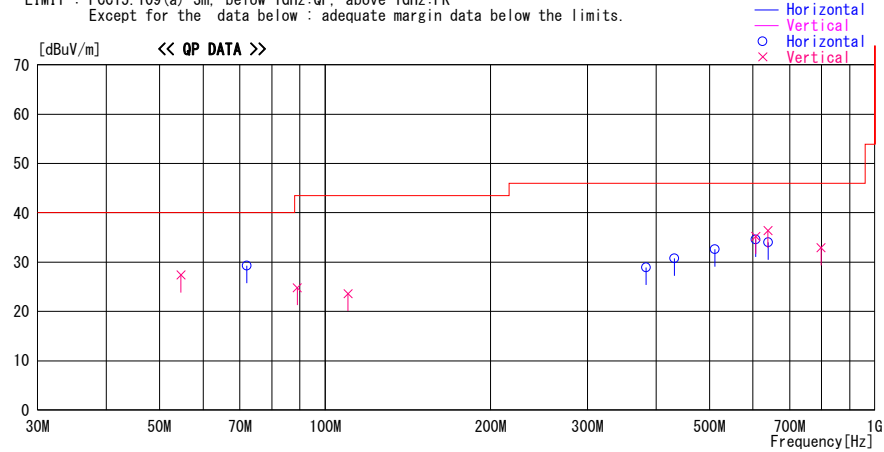
Report No. : 10249276H

Temp./Humi. : 20deg. C / 32% RH

Engineer : Keisuke Kawamura

Mode / Remarks : Standby Mode Worst-Axis (Hori: X / Vert: X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency	Reading	DET	Antenna Factor	Loss & Gain	Level	Angle	Height	Polar.	Limit	Margin	Comment
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]	
54.705	49.0	QP	9.3	-30.9	27.4	124	100	Vert.	40.0	12.6	
72.017	53.7	QP	6.4	-30.8	29.3	101	262	Hori.	40.0	10.7	
88.978	46.8	QP	8.5	-30.5	24.8	161	100	Vert.	43.5	18.7	
110.081	42.2	QP	11.6	-30.2	23.6	134	100	Vert.	43.5	19.9	
383.456	39.4	QP	16.7	-27.2	28.9	259	100	Hori.	46.0	17.1	
431.993	40.1	QP	17.5	-26.8	30.8	350	100	Hori.	46.0	15.2	
511.268	40.6	QP	18.3	-26.3	32.6	134	100	Hori.	46.0	13.4	
607.133	41.3	QP	19.5	-25.6	35.2	345	117	Vert.	46.0	10.8	
607.133	40.7	QP	19.5	-25.6	34.6	153	155	Hori.	46.0	11.4	
639.008	42.1	QP	19.7	-25.4	36.4	175	100	Vert.	46.0	9.6	
639.096	39.7	QP	19.7	-25.4	34.0	150	145	Hori.	46.0	12.0	
798.140	35.6	QP	22.0	-24.7	32.9	89	100	Vert.	46.0	13.1	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Above 1GHz)

DATA OF RADIATED EMISSION TEST

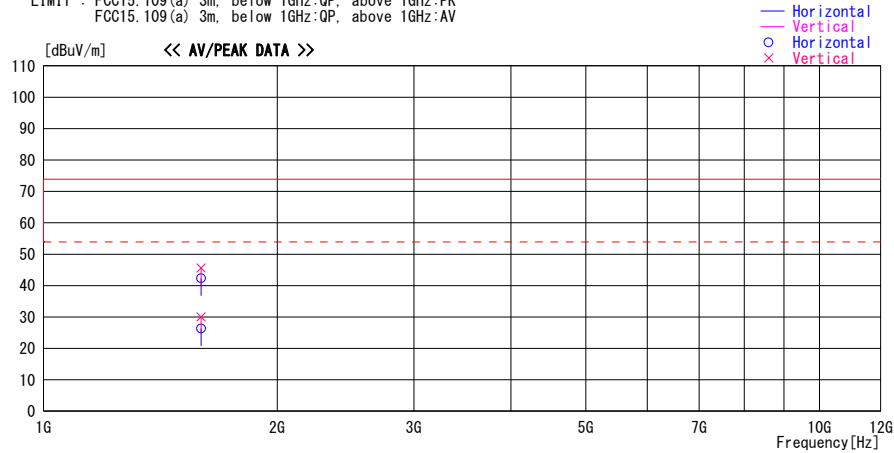
UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2014/03/10

Report No. : 10249276H

Temp./Humi. : 20deg. C / 32% RH
Engineer : Keisuke Kawamura

Mode / Remarks : USB Data Com Mode Worst-Axis (Hori: X / Vert: X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency	Reading	DET	Antenna Factor	Loss& Gain	Level	Angle	Height	Polar.	Limit	Margin	Comment
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]	
1596.054	52.2	PK	24.9	-34.7	42.4	359	131	Hori.	73.9	31.5	
1596.054	55.4	PK	24.9	-34.7	45.6	0	100	Vert.	73.9	28.3	
1596.054	39.9	AV	24.9	-34.7	30.1	0	100	Vert.	53.9	23.8	
1596.054	36.2	AV	24.9	-34.7	26.4	359	131	Hori.	53.9	27.5	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION:RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Above 1GHz)

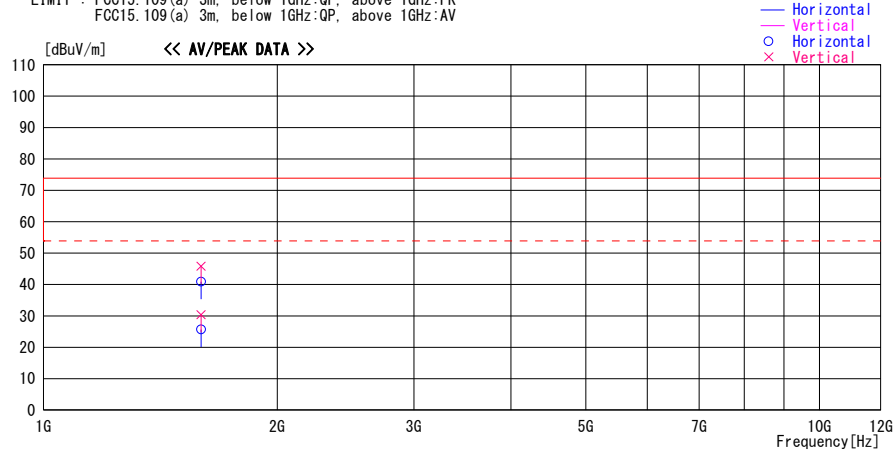
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2014/03/10

Report No. : 10249276H
Temp./Humi. : 20deg. C / 32% RH
Engineer : Keisuke Kawamura

Mode / Remarks : Standby Mode Worst-Axis (Hori: X / Vert: X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency	Reading	DET	Antenna Factor	Loss & Gain	Level	Angle	Height	Polar.	Limit	Margin	Comment
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]	
1596.054	50.7	PK	24.9	-34.7	40.9	359	131	Hori.	73.9	33.0	
1596.054	55.6	PK	24.9	-34.7	45.8	0	100	Vert.	73.9	28.1	
1596.054	40.2	AV	24.9	-34.7	30.4	0	100	Vert.	53.9	23.5	
1596.054	35.5	AV	24.9	-34.7	25.7	359	131	Hori.	53.9	28.2	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

APPENDIX 2: Test instruments

EMI Test Instruments

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 10m	DA-06881	RE/CE	2013/08/01 * 12
MOS-27	Thermo-Hygrometer	CUSTOM	CTH-201	A08Q26	RE/CE	2014/02/20 * 12
MJM-21	Measure	KOMELON	KMC-36	-	RE/CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MTR-09	EMI Test Receiver	Rohde & Schwarz	ESU26	100412	RE/CE	2013/06/07 * 12
KBA-05	Biconical Antenna	Schwarzbeck	BBA9106	2513	RE	2013/11/24 * 12
KLA-04	Logperiodic Antenna	Schwarzbeck	USLP9143	361	RE	2013/11/24 * 12
MAT-08	Attenuator(6dB)	Weinschel Corp	2	BK7971	RE	2013/11/26 * 12
MCC-02	Coaxial Cable	Suhner/storm/Agilent/TSJ	-	-	RE	2013/09/12 * 12
MPA-19	Pre Amplifier	MITEQ	MLA-10K01-B01-35	1237616	RE	2014/02/17 * 12
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2013/05/13 * 12
MPA-01	Pre Amplifier	Agilent	8449B	3008A01671	RE	2014/02/05 * 12
MCC-165	Microwave Cable	Junkosha	MWX221	1203S213(1m) / 1311S166(5m)	RE	2013/11/27 * 12
MLS-02	LISN(AMN)	Schwarzbeck	NSLK8127	8127383	CE(AE)	2013/07/11 * 12
MLS-07	LISN(AMN)	Schwarzbeck	NSLK8127	8127364	CE(EUT)	2014/01/27 * 12
MTA-28	Terminator	TME	CT-01	-	CE	2013/11/26 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/TSJ	5D-2W(20m)/ 3D-2W(7.5m)/ RG400u(1.5m)/ RFM-E421(Switcher)	-/01068(Switcher)	CE	2013/09/12 * 12
MAT-64	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2014/01/29 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

CE: Conducted Emissions

RE: Radiated Emissions

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